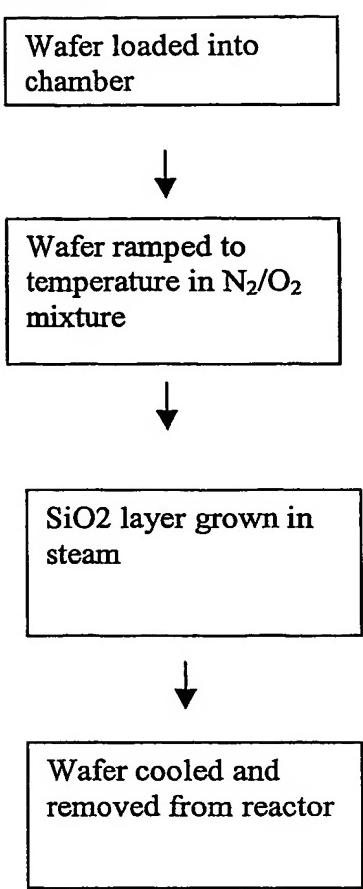
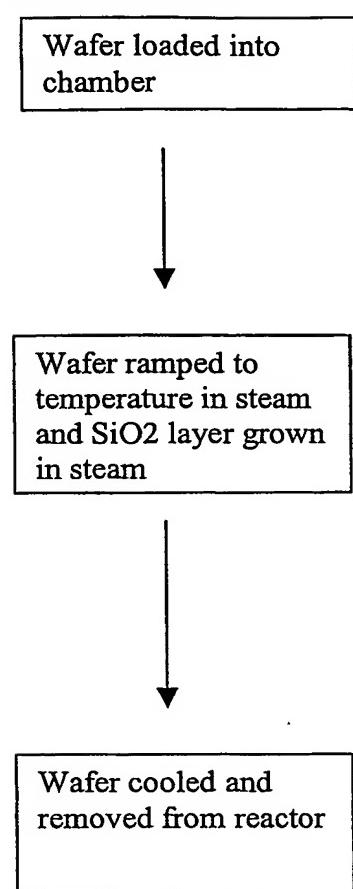
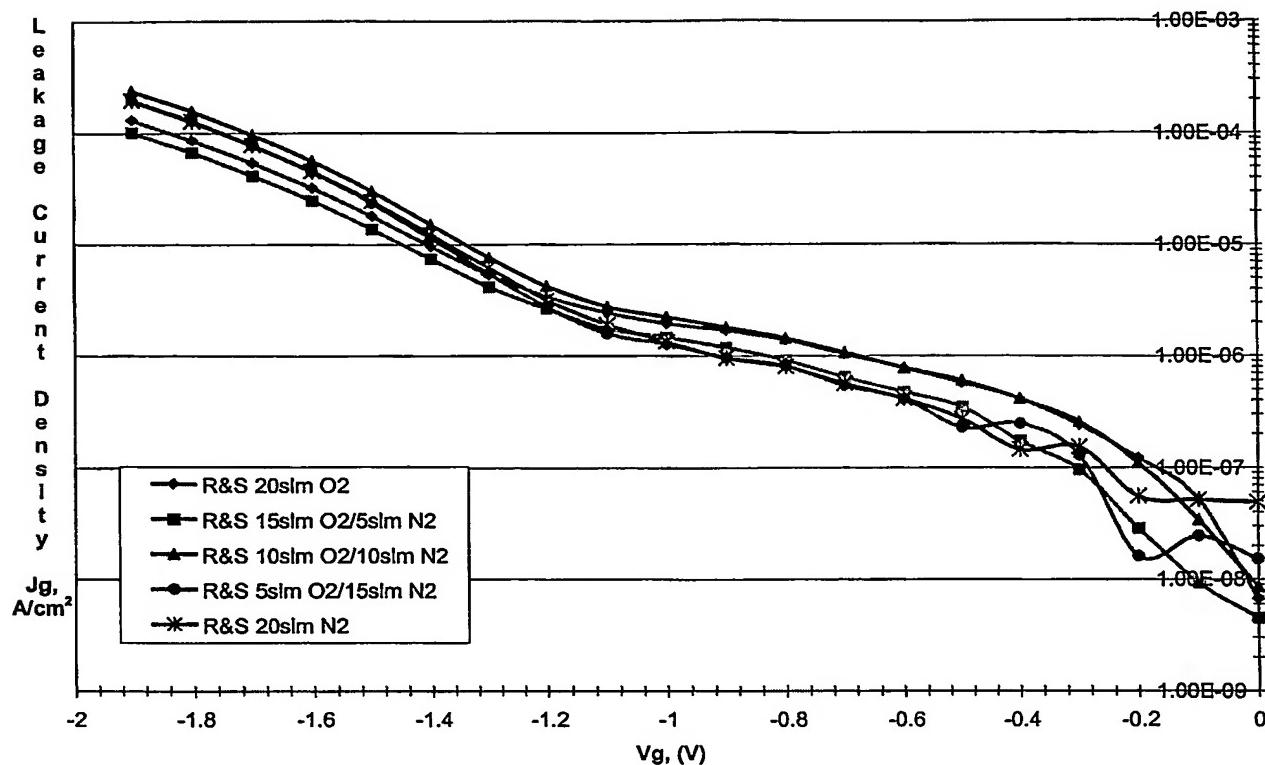
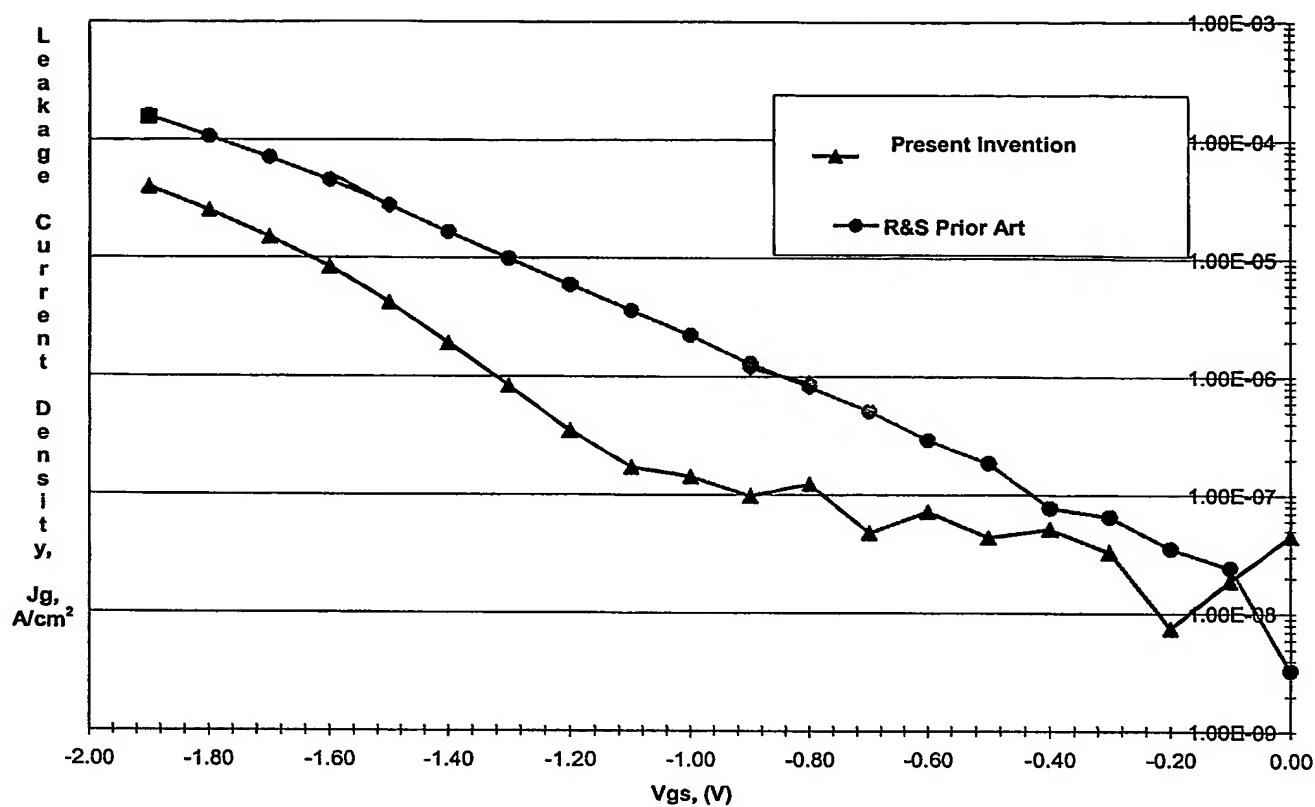


**FIG. 1A**Prior Art**FIG. 1B**Present Invention

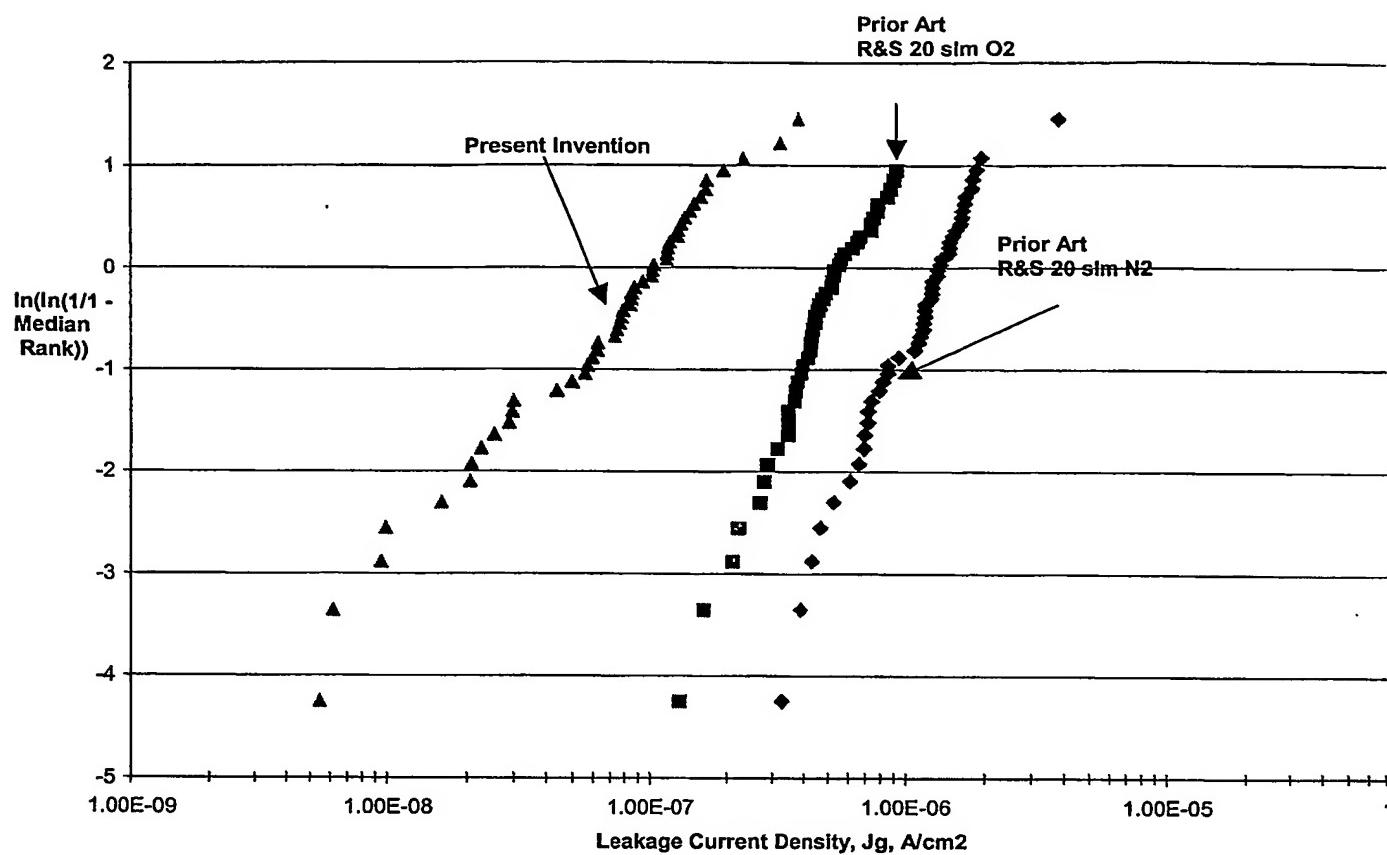


**FIG. 2**

Leakage Current Density vs  $V_{gs}$  Charts for 900°C Wet Oxidation Using Various Oxygen Flows During Ramp & Stabilization Step as practiced in the prior art.



**FIG. 3**  
Leakage current density ( $J_g$ ) vs  $V_{gs}$  for wet oxidation processes at different process temperatures.



**FIG. 4**  
Weibull plots for wet oxidation processes with and without ramp and stabilization step at 900°C